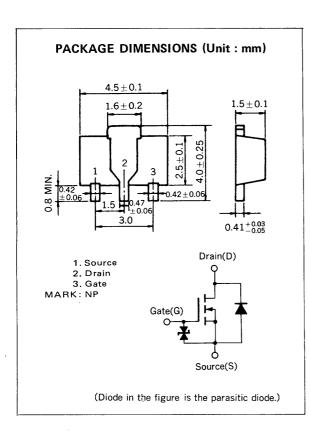
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P1 98.2



MOS FIELD EFFECT TRANSISTOR **2SK1593**

N-CHANNEL MOS FET FOR SWICHING



The 2SK1593, N-channel vertical type MOS FET, is a switching device which can be driven directly by the output of ICs having a 5 V power source.

As the MOS FET has low on-state resistance and excellent switching characteristics, it is suitable for driving actuators such as motors, relays, and solenoids.

FEATURES

- Directly driven by ICs having a 5 V power source.
- Has low on-state resistance.

 $R_{DS(on)1} = 6.0 \Omega MAX$. @ $V_{GS} = 4.0 V$, $I_{D} = 0.3 A$ $R_{DS(on)2} = 5.0 \Omega MAX$. @ $V_{GS} = 10 V$, $I_{D} = 0.3 A$

QUALITY GRADE

Standard

Please refer to "Quality grade on NEC Semiconductor Devices" (Document number IEI-1209) published by NEC Corporation to know the specification of quality grade on the devices and its recommended applications.

ABSOLUTE MAXIMUM RATINGS ($T_a = 25$ °C)

PARAMETER	SYMBOL	RATINGS	UNIT	TEST CONDITIONS
Drain to Source Voltage	V _{DSS}	100	V	V _{GS} = 0
Gate to Source Voltage	V _{GSS}	±20	V	V _{DS} = 0
Drain Current	ID(DC)	±500	mA	
Drain Current	I _{D(pulse)}	±1.0	Α	PW \leq 10 ms, Duty Cycle \leq 50 %
Total Power Dissipation	PT	2.0	w	When using ceramic board of 16 cm ² x 0.7 mm
Channel Temperature	T _{ch}	150	°C	
Storage Temperature	T _{stg}	-55 to +150	°C	

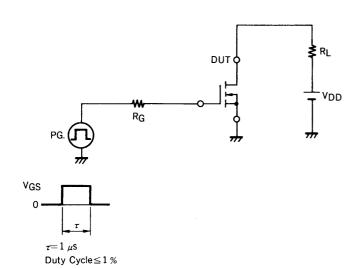
Document No. TC-2302B (0.D.No. TC-7727B) Date Published November 1994 M Printed in Japan

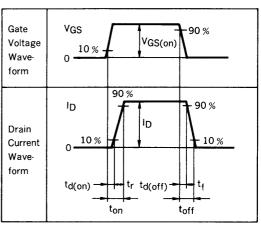


ELECTRICAL CHARACTERISTICS (T_a = 25 °C)

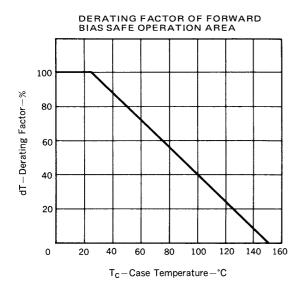
PARAMETER	SYMBOL	MIN.	TYP.	MAX.	UNIT	TEST CONDITIONS
Drain Cut-off Current	¹ DSS			10	μА	V _{DS} = 100 V, V _{GS} = 0
Gate Leakage Current	^I GSS			±10	μА	V _{GS} = ±20 V, V _{DS} = 0
Gate Cut-off Voltage	VGS(off)	0.8	1.3	2.0	V	V _{DS} = 10 V, I _D = 1 mA
Forward Transfer Admittance	ly _{fs} l	0.4	0.5		S	V _{DS} = 10 V, I _D = 0.5 A
Drain to Source On-State Resistance	RDS(on)1		4.0	6.0	Ω	V _{GS} = 4.0 V, I _D = 0.3 A
Drain to Source On-State Resistance	R _{DS} (on)2		3.4	5.0	Ω	V _{GS} = 10 V, I _D = 0.3 A
Input Capacitance	C _{iss}		55		pF	
Output Capacitance	Coss		25		pF	V _{DS} = 10 V, V _{GS} = 0, f = 1 MHz
Feedback Capacitance	C _{rss}		4.5		рF	
Turn-On Delay Time	^t d(on)		60		ns	
Rise Time	t _r		140		ns	$V_{DD} = 10 \text{ V, } I_{D} = 0.3 \text{ A}$ $V_{GS(on)} = 4 \text{ V, } R_{G} = 10 \Omega$ $R_{I} = 33 \Omega$
Turn-Off Delay Time	^t d(off)		140		ns	
Fall Time	tf		90		ns] -

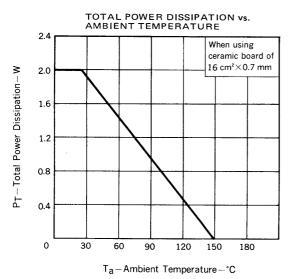
SWITCHING TIME MEASUREMENT CIRCUIT AND CONDITIONS

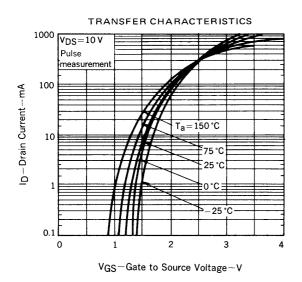


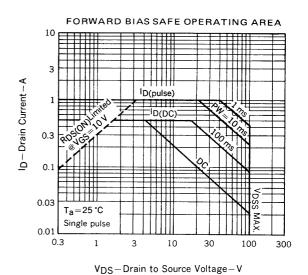


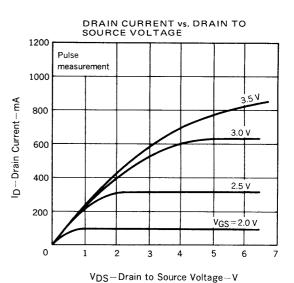
TYPICAL CHARACTERISTICS (T_a = 25 °C)

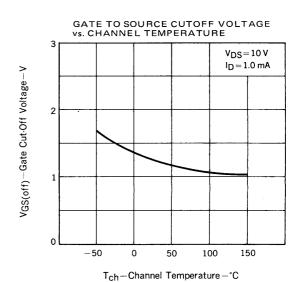


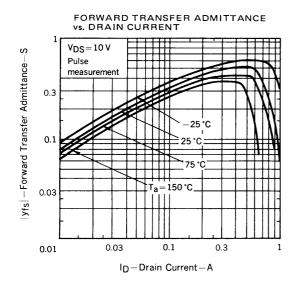


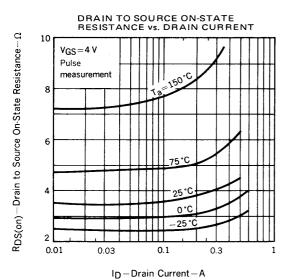


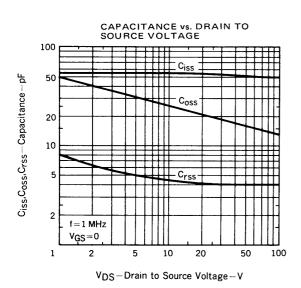


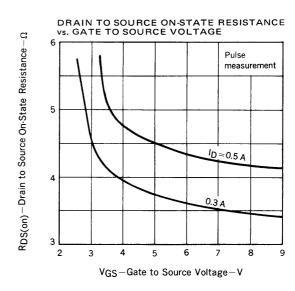


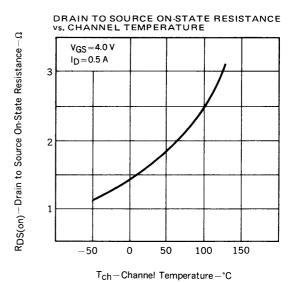


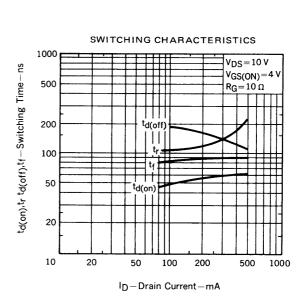


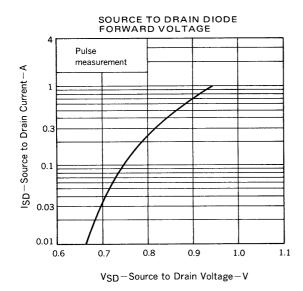












RECOMMENDED SOLDERING CONDITIONS

Mouning of this product by soldering should be done under the following conditions.

Please consult our representatives about soldering methods and conditions other than these.

SURFACE MOUNT TYPE

For details of the recommended soldering conditions, see the information document "SMT MANUAL" (IEI-1207).

Soldering Method	Soldering Conditions	Symbol for Recommended Conditions
Infrared Reflow	Package peak temp.: 230 °C Soldering time: within 30 sec (above 210 °C) Soldering times: 1, Days limitation: none*	IR30-00
Vapor Phase Soldering	Package peak temp.: 215 °C Soldering time: within 40 sec (above 200 °C) Soldering times: 1, Days limitation: none*	VP15-00
Wave Soldering	Soldering bath temp.: below 260 °C Soldering time: within 10 sec Soldering times: 1, Days limitation: none*	WS60-00

^{*:} Stored days under storage conditions at 25 °C and below 65 % R.H. after the dry-pack has been opened.

Note 1 Combination of soldering methods should be avoided.

REFERENCE

Document Name	Document No. TEI-1202	
NEC semiconductor device reliability/quality control system.		
Quality grade on NEC semiconductor devices.	IEI-1209	
Semiconductor device mounting technology manual.	IEI-1207	
Semiconductor device package manual.	IEI-1213	
Guide to quality assurance for semiconductor devices.	MEI-1202	
Semiconductor selection guide.	MF-1134	

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Standard: Computer, Office equipment, Communication equipment, Test and Measurement equipment, Machine tools, Industrial robots, Audio and Visual equipment, Other consumer products, etc.

Special: Automotive and Transportation equipment, Traffic control systems, Antidisaster systems, Anticrime systems, etc.